

TEST REPORT

For

Bluetooth Low Energy Wireless Module

In conformity with

FCC CFR 47 Part15 Subpart C

Model : MK71050-03

FCC ID : 2ACIJ71050-3

Report No. : **ERY1410P10R9**

Issue Date : 10 Oct. 2014

Prepared for

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Prepared by

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SGS RF Technologies Inc. Page 1 of 29



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SGS RF Technologies Inc. is managed to ISO17025 and has the necessary knowledge and test facilities for testing according to the referenced standards. The test results in this report apply only to the sample(s) tested.

SGS RF Technologies Inc. Page 2 of 29

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Table of contents

1 Ge	eneral informationeneral information	4
1.1	Product description	
1.2	Test(s) performed/ Summary of test result	4
1.3	Test facility	
1.4	Measurement uncertainty	
1.5	Summary of test results	<i>6</i>
1.6	Setup of equipment under test (EUT)	6
1.6	.1 Test configuration of EUT	6
1.6	.2 Operating condition:	6
1.6	.3 Setup diagram of tested system	7
1.7	Equipment modifications	
1.8	Deviation from the standard	7
2 Te	st procedure and test data	8
2.1	Occupied Bandwidth (99%)	8
2.2	6dB Bandwidth	10
2.3	Peak Output Power	12
2.4	Conducted Spurious Emissions	14
2.5	Power Spectral density	18
2.6	Radiated emissions	20
2.7	AC power line conducted emissions	25
3 Te	st setup photographs	28
3.1	Radiated emissions	
3.2	AC power line conducted emissions	
4 Lis	st of utilized test equipment / calibration	

History

Report No.	Date	Revisions	Issued By
ERY1410P10R9	10 Oct. 2014	Initial Issue	T.Kato



Issue Date: 10 Oct. 2014 Report No.: ERY1410P10R9

Model: MK71050-03

General information

1.1 Product description

Test item

: Bluetooth Low Energy Wireless Module

Manufacturer

: LAPIS Semiconductor Co., Ltd.

Address

: 2-4-8 Shinyokohama, Kouhoku-ku, Yokohama 222-8575 Japan

Model

: MK71050-03

FCC ID

: 2ACIJ71050-3

Serial number

: 302, 306

Software version

: config for ML7105-001 Ver3.01

Hardware version

: DS10

Operating frequency

: 2402 - 2480 MHz

Modulation

: GFSK

Receipt date of EUT

: 10 Sep. 2014

Nominal power source voltages : 3.3 Vdc

1.2 Test(s) performed/Summary of test result

Test specification(s)

: FCC CFR 47 Part 15 Subpart C (01 Oct. 2013)

Test method(s)

: ANSI C63.10: 2010

Test(s) started

KDB Publication No. 558074 : 15 Sep. 2014

Test(s) completed

: 22 Sep. 2014

Purpose of test(s)

: Certification

Summary of test result

: Complied

Note: The above judgment is only based on the measurement data and it does not include the measurement uncertainty. Accordingly, the statement below is applied to the test result.

The EUT complies with the limit required in the standard in case that the margin is not less than the measurement uncertainty in the Laboratory.

Compliance of the EUT is more probable than non-compliance is case that the margin is less than the measurement uncertainty in the Laboratory.

Test engineer

T. Kato

EMC testing Department

Reviewer

K. Onishi

Manager

EMC testing Department

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1.3 Test facility

The Federal Communications Commission has reviewed the technical characteristics of the test facilities at SGS RF Technologies Inc., located in 472, Nippa-cho, Kohoku-ku, Yokohama, 223-0057, Japan, and has found these test facilities to be in compliance with the requirements of 47 CFR Part 15, section 2.948, per October 1, 2013.

The description of the test facilities has been filed under registration number 319924 at the Office of the Federal Communications Commission. The facility has been added to the list of laboratories performing these test services for the public on a fee basis.

The list of all public test facilities is available on the Internet at http://www.fcc.gov.

Registered by Industry Canada (IC): The registered facility number is as follows; Test site No. 1 (Semi-Anechoic chamber 3m): 6974A-1

Accredited by **National Voluntary Laboratory Accreditation Program** (NVLAP) for the emission tests stated in the scope of the certificate under Certificate Number 200780-0

This report must not be used by the client to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.

1.4 Measurement uncertainty

The treatment of uncertainty is based on the general matters on the definition of uncertainty in "Guide to the expression of uncertainty in measurement (GUM)" published by ISO. The Lab's uncertainty is determined by referring UKAS Publication LAB34: 2002 "The Expression of Uncertainty in EMC Testing" and CISPR16-4-2: 2011 "Uncertainty in EMC Measurements".

The uncertainty of the measurement result in the level of confidence of approximately 95% (k=2) is as follows;

Conducted emission: \pm 3.4 dB (10 kHz - 30 MHz) Radiated emission (9 kHz - 30 MHz): \pm 3.8 dB Radiated emission (30 MHz - 200 MHz): \pm 5.0 dB Radiated emission (200 MHz - 1000 MHz): \pm 6.2 dB

SGS RF Technologies Inc. Page 5 of 29

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1.5 Summary of test results

Requirement	Section in specification	Result	Section in this report
Occupied Bandwidth (99 %)	2.1049	Complied	2.1
6 dB Bandwidth	15.247 (a) (2)	Complied	2.2
Conducted Output Power	15.247 (b) (3)	Complied	2.3
Conducted Spurious Emission	15.247 (d)	Complied	2.4
Power Spectral Density	15.247 (e)	Complied	2.5
Radiated Emissions	15.247(d), 15.205 (a)	Complied	2.6
AC power line conducted emissions	15.207	Complied	2.7

1.6 Setup of equipment under test (EUT)

1.6.1 Test configuration of EUT

Equipment(s) under test

	(~	.) ======			
	No.	Item	Manufacture	Model No.	Serial No.
ı	A1	Bluetooth Module (for Conducted test)	LAPIS Semiconductor	MK71050-03	302
ı	A2	Bluetooth Module (for Radiated test)	LAPIS Semiconductor	MK71050-03	306

Support Equipment(s)

<u> re Bqe</u>	ipinent(s)			
No.	Item	Manufacture	Model No.	Serial No.
В	Conversion Board	-	-	-
C	RS-232C Converter	-	-	-
D	AC adaptor	UNIFIVE	US303320	D02-0136115

Connected cable(s)

-					
No.	Item	Identification	Cable	Ferrite	Length
		(Manu.etc.)	Shielded	Core	[m]
1	DC cable for AC adaptor	-	No	No	1.0

1.6.2 Operating condition:

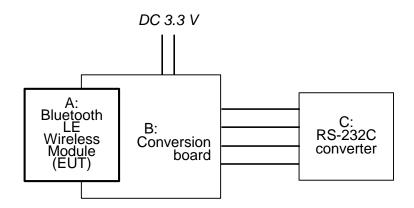
- Tx (2402MHz): The EUT is in normal transmission mode in 2402 MHz.
- Tx (2440MHz): The EUT is in normal transmission mode in 2440 MHz.
- Tx (2480MHz): The EUT is in normal transmission mode in 2480 MHz.

SGS RF Technologies Inc. Page 6 of 29

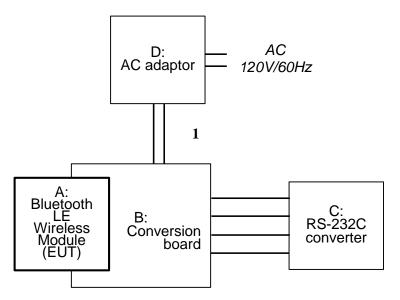


1.6.3 Setup diagram of tested system

[Configuration A]



[Configuration B]



1.7 Equipment modifications

No modifications have been made to the equipment in order to achieve compliance with the applicable standards described in clause 1.2.

1.8 Deviation from the standard

No deviations from the standards described in clause 1.2.

SGS RF Technologies Inc. Page 7 of 29



2 Test procedure and test data

2.1 Occupied Bandwidth (99%)

Test setup

Test setup is the following drawing. The antenna port of EUT was connected to the spectrum analyzer.



Test procedure

Spectrum analyzer is set as below according to ANSI C63.10 clause 6.9

- RBW = 20 kHz - VBW > 3 x RBW

- Detector : Peak

Limitation

There are no limitations.

The measurement value is used for the emission designator.

Test equipment used (refer to List of utilized test equipment)

TR06	CL31		

Test results

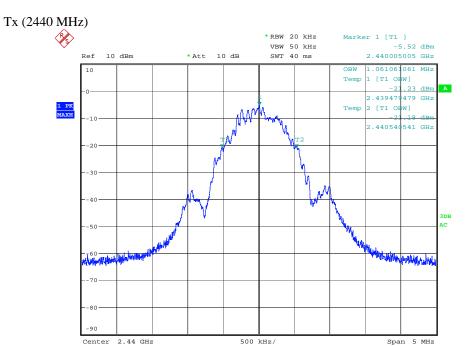
Configuration: A Tested sample: A1

Transmission Frequency [MHz]	Occupied Bandwidth [MHz]			
2402	1.068			
2440	1.061			
2480	1.081			

SGS RF Technologies Inc. Page 8 of 29



[Chart]



Tested Date: 17 Sep. 2014 Temperature: 20 degC Humidity: 56 % Atmos. Press: 1015 hPa

SGS RF Technologies Inc. Page 9 of 29



2.2 6dB Bandwidth

Test setup

Test setup is the following drawing. The antenna port of EUT was connected to the spectrum analyzer.



Test procedure

Spectrum analyzer is set as below according to KDB 558074 clause 8.1

-RBW = 100 kHz

 $-VBW > 3 \times RBW$

- Detector : Peak

Applicable rule and limitation

15.247 (a) (2) Systems using digital modulation techniques may operate in the 902–928 MHz, 2400–2483.5 MHz, and 5725–5850 MHz bands. The minimum 6 dB bandwidth shall be at least 500 kHz.

Test equipment used (refer to List of utilized test equipment)

Test results - **Complied with requirement**

Test Data

Configuration: A
Tested sample: A1

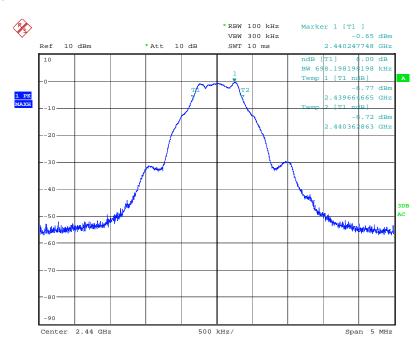
Transmission	6 dB Bandwidth [kHz]
Frequency [MHz]	[KIIZ]
2402	708
2440	698
2480	701

SGS RF Technologies Inc. Page 10 of 29



[Chart]

Tx 2440 MHz



Tested Date: 17 Sep. 2014 Temperature: 20 degC Humidity: 56 % Atmos. Press: 1015 hPa

SGS RF Technologies Inc. Page 11 of 29



2.3 Peak Output Power

Test setup

Test setup is the following drawing. The antenna port of EUT was connected to the spectrum analyzer.



Test procedure

Spectrum analyzer is set as below according to KDB 558074 clause 9.1.1

 $\begin{array}{lll} - \mbox{ Span} > 3 \mbox{ x RBW} & - \mbox{ RBW} > 6 \mbox{dB BW} \\ - \mbox{ VBW} > 3 \mbox{ x RBW} & - \mbox{ Detector} : \mbox{ Peak} \end{array}$

Applicable rule and limitation

15.247(b) (3) For systems using digital modulation in the 902–928 MHz, 2400–2483.5MHz, and 5725–5850 MHz bands: 1 Watt (30 dBm).

Test equipment used (refer to List of utilized test equipment)

TDOC	CT 21		
TR06	CL31		

Test results - Complied with requirement

Test Data

Configuration: A
Tested sample: A1

resicu sumpie. 111	resieu sampie. 111				
Transmission Frequency [MHz]	Output Power [dBm]				
2402	0.15				
2440	0.22				
2480	-0.11				

SGS RF Technologies Inc. Page 12 of 29



[Chart]

Tx 2440 MHz



Tested Date: 17 Sep. 2014 Temperature: 20 degC Humidity: 56 % Atmos. Press: 1015 hPa

SGS RF Technologies Inc. Page 13 of 29



2.4 Conducted Spurious Emissions (for non-restricted frequency band)

Test setup

Test setup is the following drawing. The antenna port of EUT was connected to the spectrum analyzer.



Test procedure

Spectrum analyzer is set as below according to KDB 558074 clause 11.2 and 11.3

- Span > 1.5 x [6dB BW] - RBW = 100 kHz- VBW > 300 kHz - Detector : Peak

Limitation

15.247(d) In any 100 kHz bandwidth outside the frequency band in which the spread spectrum or digitally modulated intentional radiator is operating, the radio frequency power that is produced by the intentional radiator shall be at least 20 dB below that in the 100 kHz bandwidth within the band that contains the highest level of the desired power, based on either an RF conducted or a radiated measurement, provided the transmitter demonstrates compliance with the peak conducted power limits.

Test equipment used (refer to List of utilized test equipment)

TR06	CL31		

Test results - **Complied with requirement**

Test Data

Configuration: A
Tested sample: A1

Operating mode: Tx (2402 MHz)

Frequency	Spurius level	Carrier level	20dB below
[MHz]	[dBm]	[dBm]	[dBm]
4804.500	-43.50	-0.84	-20.84
9607.000	-48.63	-0.84	-20.84

Operating mode: Tx (2440 MHz)

Frequency	Spurius level	Carrier level	20dB below
[MHz]	[dBm]	[dBm]	[dBm]
4880.000	-46.66	-1.14	-21.14
9760.000	-49.98	-1.14	-21.14

Operating mode: Tx (2480 MHz)

Frequency [MHz]	Spurius level [dBm]	Carrier level [dBm]	20dB below [dBm]
4959.600	-44.19	-1.08	-21.08
9919.000	-50.94	-1.08	-21.08

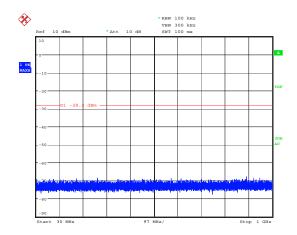
SGS RF Technologies Inc. Page 14 of 29

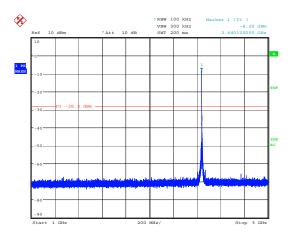
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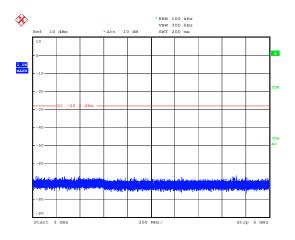


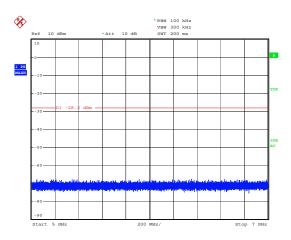
[Chart]

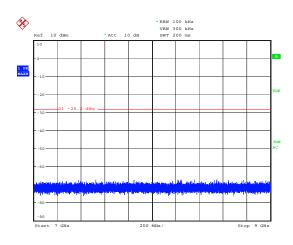
Tx 2440 MHz

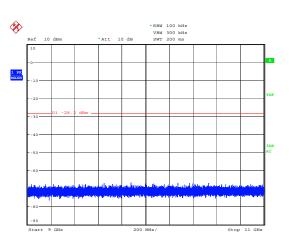








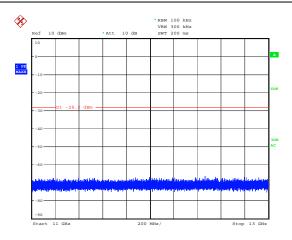


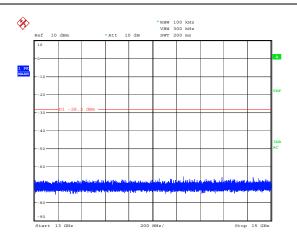


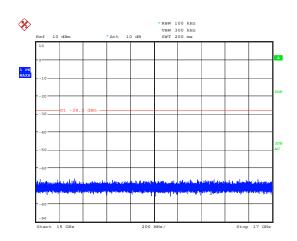
SGS RF Technologies Inc. Page 15 of 29

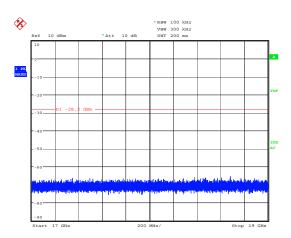
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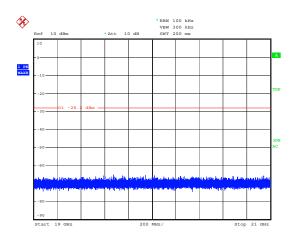


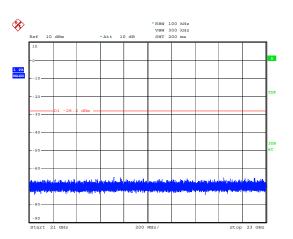




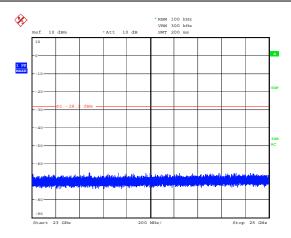












17 Sep. 2014 20 degC 1015 hPa Tested Date: Temperature: Humidity: 56 % Atmos. Press:

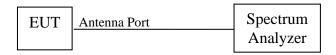
Page 17 of 29



2.5 Power Spectral density

Test setup

Test setup is the following drawing. The antenna port of EUT was connected to the spectrum analyzer.



Test procedure

Spectrum analyzer is set as below according to KDB 558074 clause 10.2

- Span > 1.5 x [6dB BW] - RBW = 3 kHz

 $-VBW > 3 \times RBW$ - Detector : Peak

Limitation

15.247(e) For digitally modulated systems, the power spectral density conducted from the intentional radiator to the antenna shall not be greater than 8 dBm in any 3 kHz band during any time interval of continuous transmission.

Test equipment used (refer to List of utilized test equipment)

TR06	CL31		
11100	0201		

Test results - Complied with requirement

Test Data

Configuration: A
Tested sample: A1

Transmission Frequency [MHz]	Spectral Density [dBm]
2402	-14.26
2440	-13.80
2480	-14.47

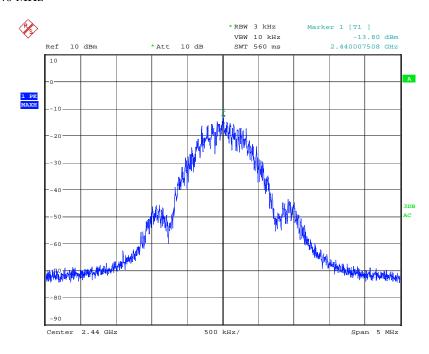
SGS RF Technologies Inc. Page 18 of 29

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[Chart]

Tx 2440 MHz



Tested Date: 17 Sep. 2014 Temperature: 20 degC Humidity: 56 % Atmos. Press: 1015 hPa

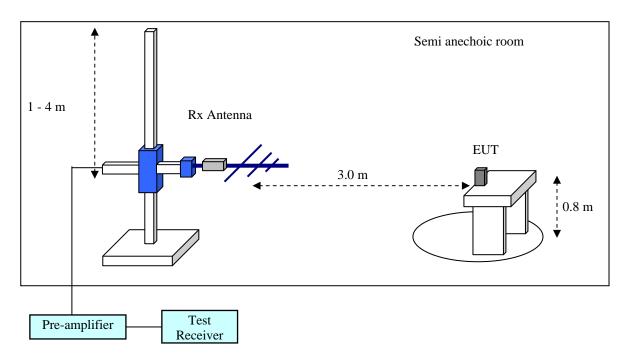
SGS RF Technologies Inc. Page 19 of 29



2.6 Radiated emissions (for restricted frequency band)

Test setup

Test setup was implemented according to the method of ANSI C63.10: 2013 clause 6.



Test procedure

Measurement procedures were implemented according to the method of ANSI C63.10: 2013 clauses 6. The test receiver is set as below

[below 1000 MHz]

RBW: 120 kHz, Detector: QP

[above 1000 MHz]

RBW: 1 MHz, Detector: Ave/PK

SGS RF Technologies Inc. Page 20 of 29



Applicable rule and limitation

FCC 15.205 restricted bands of operation

Except as shown in paragraph 15.205 (d) of this section, only spurious emissions are permitted in any of the frequency bands listed below:

the frequency bands fisted t	CIOW.		
MHz	MHz	MHz	GHz
0.090 - 0.110	16.42 - 16.423	399.9 - 410	4.5 - 5.15
0.490 - 0.510	16.69475 - 16.69525	608 - 614	5.35 - 5.46
2.1735 - 2.1905	16.80425 - 16.80475	960 - 1240	7.25 - 7.75
4.125 - 4.128	25.5 - 25.67	1300 - 1427	8.025 - 8.5
4.17725 - 4.17775	37.5 - 38.25	1435 - 1626.5	9.0 - 9.2
4.20725 - 4.20775	73 - 74.6	1645.5 - 1646.5	9.3 - 9.5
6.215 - 6.218	74.8 - 75.2	1660 - 1710	10.6 - 12.7
6.26775 - 6.26825	108 - 121.94	1718.8 - 1722.2	13.25 - 13.4
6.31175 - 6.31225	123 - 138	2200 - 2300	14.47 - 14.5
8.291 - 8.294	149.9 - 150.05	2310 - 2390	15.35 - 16.2
8.362 - 8.366	156.52475 - 156.52525	2483.5 - 2500	17.7 - 21.4
8.37625 - 8.38675	156.7 - 156.9	2690 - 2900	22.01 - 23.12
8.41425 - 8.41475	162.0125 - 167.17	3260 - 3267	23.6 - 24.0
12.29 - 12.293	167.72 - 173.2	3332 - 3339	31.2 - 31.8
12.51975 - 12.52025	240 - 285	3345.8 - 3358	36.43 - 36.5
12.57675 - 12.57725	322 - 335.4	3600 - 4400	38.6 -

The field strength of emissions appearing within these frequency bands shall not exceed the limits shown in FCC 15.209. At frequencies equal to or less than 1000 MHz, compliance with the limits in FCC 15.209 shall be demonstrated using measurement instrumentation employing a CISPR quasi-peak detector. Above 1000 MHz, compliance with the emission limits in Section 15.209 shall be demonstrated based on the average value of the measured emissions.

FCC 15.209 Field strength limits

2 10 12 0								
Frequency [MHz]	Field Strength [µV/m]	Measurement Distance [m]	Field Strength [dBµV/m]					
30 - 88	100	3	40.0					
88 –216	150	3	43.5					
216 – 960	200	3	46.0					
Above 960	500	3	53.9					

In the emission table above, the tighter limit applies at the band edges.

The emission limits shown in the above table are based on measurements employing a quasi-peak detector.

Test results - <u>Complied with requirement</u>

SGS RF Technologies Inc. Page 21 of 29



Test equipment used (refer to List of utilized test equipment)

AC01(EM)	CL11	TR06	PR15	BA10	CL30	CL31
PR12	DH01					

Test software used

30 - 1000 MHz testing: EMI Ver. 5.6 above 1000 MHz testing: EMI_GHz Ver 4.3

Calculation method

The Correction Factor and Result are calculated as followings.

Correction Factor [dB/m] = Ant. Factor [dB/m] + Loss [dB] – Gain [dB] Result [dB μ V/m] = Reasding [dB μ V] + Correction Factor [dB/m]

Test Data

Configuration: A
Tested sample: A2

Operating mode: Tx (2402 MHz)

[Emission level] X-plane

No.	Frequency [MHz]	Reading PK [dBµV]	Reading Ave [dBµV]	C.Factor [dB]	PK	Result Ave [dBµV/m]	Limit PK [dBµV/m]	Limit Ave [dBµV/m]	Ant.
1	2390.000	45.9	32.8	-4.5	41.4	28.3	73.9	53.9	Hori.
2	4804.000	53.1	49.4	2.4	55.5	51.8	73.9	53.9	Hori.
3	12010.000	41.7	28.7	3.7	45.4	32.4	73.9	53.9	Vert.

[Emission level] Y-plane

No.	Frequency [MHz]	Reading PK [dBµV]	Reading Ave [dBµV]	C.Factor	PK	Result Ave [dBµV/m]	Limit PK [dBµV/m]	Limit Ave [dBµV/m]	Ant.
1	2390.000	45.9	32.5	-4.5	41.4	28.0	73.9	53.9	Hori.
2	4804.000	52.3	47.9	2.4	54.7	50.3	73.9	53.9	Vert.
3	12010.000	42.3	29.6	3.7	46.0	33.3	73.9	53.9	Hori.

[Emission level] Z-plane

No.	Frequency [MHz]	Reading PK [dBµV]	Reading Ave [dBµV]	C.Factor	PK	Result Ave [dBµV/m]	Limit PK [dBµV/m]	Limit Ave [dBµV/m]	Ant.
1	2390.000	45.1	32.6	-4.5	40.6	28.1	73.9	53.9	Hori.
2	4804.000	50.8	46.3	2.4	53.2	48.7	73.9	53.9	Vert.
3	12010.000	42.2	30.2	3.7	45.9	33.9	73.9	53.9	Vert.

SGS RF Technologies Inc. Page 22 of 29

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Operating mode: Tx (2440 MHz)

[Emission level] X-plane

No.	Frequency [MHz]	Reading PK [dBµV]	Reading Ave [dBµV]	C.Factor	PK	Result Ave [dBµV/m]	Limit PK [dBµV/m]	Limit Ave [dBµV/m]	Ant.
1	4880.000	47.4	41.4	2.5	49.9	43.9	73.9	53.9	Hori.
2	7320.000	45.1	35.3	8.5	53.6	43.8	73.9	53.9	Hori.
3	12200.000	41.4	28.2	4.0	45.4	32.2	73.9	53.9	Hori.

[Emission level] Y-plane

	Frequency	Reading	Reading	C.Factor	Result	Result	Limit	Limit	
No.	[MHz]	PK [dBµV]	Ave [dBµV]	[dB]	PK	Ave [dBµV/m]	PK [dBµV/m]	Ave [dBµV/m]	Ant.
1	4880.000	48.9	43.5	2.5	51.4	46.0	73.9	53.9	Vert.
2	7320.000	44.5	34.6	8.5	53.0	43.1	73.9	53.9	Vert.
3	12200.000	40.9	28.4	4.0	44.9	32.4	73.9	53.9	Hori.

[Emission level] Z-plane

	No.	Frequency [MHz]	Reading PK [dBµV]	Reading Ave [dBµV]	C.Factor	PK	Result Ave [dBµV/m]	Limit PK [dBµV/m]	Limit Ave [dBµV/m]	Ant.
	1	4880.000	47.4	41.3	2.5	49.9	43.8	73.9	53.9	Hori.
	2	7320.000	44.4	34.0	8.5	52.9	42.5	73.9	53.9	Hori.
I	3	12200.000	40.8	27.8	4.0	44.8	31.8	73.9	53.9	Vert.

Operating mode: Tx (2480 MHz)

[Emission level] X-plane

No.	Frequency [MHz]	Reading PK [dBµV]	Reading Ave [dBµV]	C.Factor	PK	Result Ave [dBµV/m]	Limit PK [dBµV/m]	Limit Ave [dBµV/m]	Ant.
1	2483.500	55.0	42.3	-3.7	51.3	38.6	73.9	53.9	Hori.
2	4960.000	49.4	43.9	2.8	52.2	46.7	73.9	53.9	Hori.
3	7440.000	47.0	37.4	8.0	55.0	45.4	73.9	53.9	Hori.

[Emission level] Y-plane

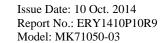
No.	Frequency [MHz]	Reading PK [dBµV]	Reading Ave [dBµV]	C.Factor	PK	Result Ave [dBµV/m]	Limit PK [dBµV/m]	Limit Ave [dBµV/m]	Ant.
1	2483.500	54.0	42.0	-3.7	50.3	38.3	73.9	53.9	Hori.
2	4960.000	47.2	40.2	2.8	50.0	43.0	73.9	53.9	Vert.
3	7440.000	45.2	34.7	8.0	53.2	42.7	73.9	53.9	Vert.

[Emission level] Z-plane

	Emission tever Z-plane												
No.	Frequency [MHz]	Reading PK [dBµV]	Reading Ave [dBµV]	C.Factor	PK	Result Ave [dBµV/m]	Limit PK [dBµV/m]	Limit Ave [dBµV/m]	Ant.				
1	2483.500	55.1	42.0	-3.7	51.4	38.3	73.9	53.9	Vert.				
2	4960.000	47.9	41.7	2.8	50.7	44.5	73.9	53.9	Hori.				
3	7440.000	45.2	34.6	8.0	53.2	42.6	73.9	53.9	Vert.				

SGS RF Technologies Inc. Page 23 of 29

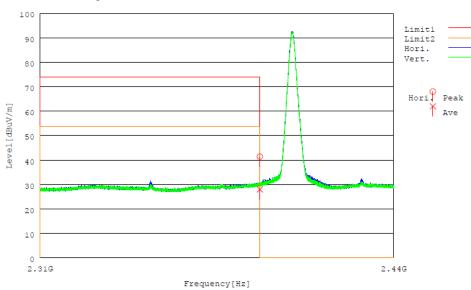
472, Nippa-cho, Kohoku-ku, Yokohama, 223-0057, Japan Telephone: +81+(0)45- 534-0645, FAX: +81+(0)45- 534-0646, Web: http://www.rf-test.jp



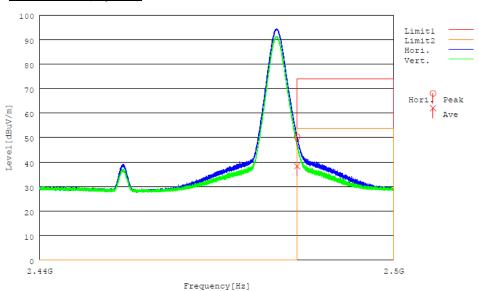
SGS

[Chart (Band edge)]

<u>Tx 2402 MHz (Y-plane)</u>



Tx 2480 MHz (Y-plane)



[30 - 1000 MHz testing]

Tested Date: 15 Sep. 2014 Temperature: 23 degC Humidity: 69 % Atmos. Press: 1015 hPa

[above 1000 MHz testing]

Tested Date: 17 Sep. 2014 Temperature: 20 degC Humidity: 56 % Atmos. Press: 1015 hPa

SGS RF Technologies Inc. Page 24 of 29



2.7 AC power line conducted emissions

Test setup

Test setup was implemented according to the method of ANSI C63.10: 2013 clause 6.

Test procedure

Measurement procedures were implemented according to the method of ANSI C63.10: 2013 clauses 6.

Applicable rule and limitation

FCC 15.207 AC power line conducted emissions limits

Frequency of Emission	Conducted emissions Limit [dBµV]				
[MHz]	Quasi-peak	Average			
0.15 - 0.5	66 to 56 *	56 to 46 *			
0.5 - 5	56	46			
5 - 30	60	50			

^{*} Decreases with the logarithm of the frequency. The lower limit applies at the band edges.

Test equipment used (refer to List of utilized test equipment)

TR09	CL18	LN05

Test software used

EMI Ver. 5.6

Calculation method

The Correction Factor and Result are calculated as followings.

$$\begin{split} & \text{Correction Factor [dB]} = ISN \text{ Factor [dB]} + Loss \text{ [dB]} \\ & \text{Result [dBμV]} = Reading \text{ [dBμV]} + Correction Factor \text{ [dB]} \end{split}$$

Test results - **Complied with requirement**

SGS RF Technologies Inc. Page 25 of 29



Test Data

Configuration: B
Tested sample: A1

Operating mode: Tx (2402 MHz)

[Emission level]

	Emaguamary	Read	ding	C.F.	Re	sult	Liı	mit		
No.	Frequency [MHz]	QP [dBµV]	ΑV [dBμV]	[dB]	QP [dBμV]	ΑV [dBμV]	QP [dBµV]	ΑV [dBμV]	Phase	Pass/Fail
1	0.17220	23.9	6.4	10.3	34.2	16.7	64.9	54.9	Va	Pass
1										
2	0.20290	21.2	7.2	10.3	31.5	17.5	63.5	53.5	Va	Pass
3	0.34865	12.1	8.0	10.2	22.3	18.2	59.0	49.0	Va	Pass
4	0.15000	27.3	7.6	10.3	37.6	17.9	66.0	56.0	Vb	Pass
5	0.16887	24.6	5.8	10.3	34.9	16.1	65.0	55.0	Vb	Pass
6	0.23804	19.7	3.8	10.2	29.9	14.0	62.2	52.2	Vb	Pass

Operating mode: Tx (2440 MHz)

[Emission level]

	Епосиотом	Read	ding	C.F.	Res	sult	Liı	nit		
No.	Frequency [MHz]	QP	AV	С.г. [dВ]	QP	AV	QP	AV	Phase	Pass/Fail
	. ,	[dBµV]	[dBµV]	L	[dBµV]	[dBµV]	[dBµV]	[dBµV]		
1	0.15000	27.3	7.7	10.3	37.6	18.0	66.0	56.0	Va	Pass
2	0.16813	24.6	6.5	10.3	34.9	16.8	65.1	55.1	Va	Pass
3	0.32979	12.3	7.5	10.2	22.5	17.7	59.5	49.5	Va	Pass
4	0.15407	26.7	6.9	10.3	37.0	17.2	65.8	55.8	Vb	Pass
5	0.19550	21.6	3.9	10.3	31.9	14.2	63.8	53.8	Vb	Pass
6	0.25173	18.6	4.1	10.2	28.8	14.3	61.7	51.7	Vb	Pass

Operating mode: Tx (2480 MHz)

[Emission level]

[231111	mission level											
	E	Rea	ding	CE	Res	sult	Liı	mit				
No.	Frequency [MHz]	QP	AV	C.F. [dB]	QP	AV	QP	AV	Phase	Pass/Fail		
	[WILIZ]	[dBµV]	[dBµV]	լաոյ	[dBµV]	[dBµV]	[dBµV]	[dBµV]				
1	0.15000	27.3	7.6	10.3	37.6	17.9	66.0	56.0	Va	Pass		
2	0.33016	12.3	7.5	10.2	22.5	17.7	59.4	49.4	Va	Pass		
3	0.34643	12.2	8.0	10.2	22.4	18.2	59.0	49.0	Va	Pass		
4	0.15000	27.1	7.1	10.3	37.4	17.4	66.0	56.0	Vb	Pass		
5	0.18070	23.3	11.3	10.3	33.6	21.6	64.5	54.5	Vb	Pass		
6	0.19661	21.4	3.7	10.3	31.7	14.0	63.8	53.8	Vb	Pass		

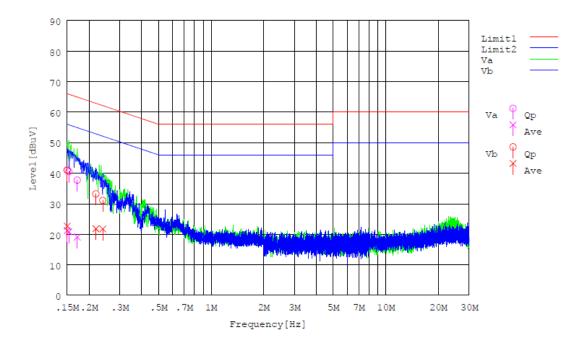
SGS RF Technologies Inc. Page 26 of 29

472, Nippa-cho, Kohoku-ku, Yokohama, 223-0057, Japan Telephone: +81+(0)45- 534-0645, FAX: +81+(0)45- 534-0646, Web: http://www.rf-test.jp



[Chart]

Operating mode: Tx (2440 MHz)



Tested Date: 22 Sep. 2014 Temperature: 23 degC Humidity: 56 % Atmos. Press: 1018 hPa

SGS RF Technologies Inc. Page 27 of 29



4 List of utilized test equipment / calibration

RFT ID No.	Kind of Equipment and Precision	Manufacturer	Model No.	Serial Number	Calibration Date	Calibrated until
AC01(EM)	Anechoic Chamber (1st test room)	JSE	203397C	-	2014/4/26	2015/4/30
AC01(EG)	Anechoic Chamber (1st test room)	JSE	203397C	-	2013/11/23	2014/11/30
BA10	Bilogical Antenna	TESEQ	CBL6111D	32342	2014/6/9	2015/6/30
CH01	Conical Horn Antenna (12-18GHz)	ETS-Lindgren	3163-05	00126641	2014/7/3	2016/7/31
CL11	Antenna Cable for RE	RFT	-	-	2014/3/31	2015/3/31
CL18	Antenna Cable for CE	RFT	-	-	2014/4/18	2015/4/30
CL29	RF Cable 2 m	SUHNER	SUCOFLEX104PE	94709	2014/1/21	2015/1/31
CL30	RF Cable 5 m	SUHNER	SUCOFLEX104PE	MY3599	2014/8/28	2015/8/31
DH01	DRG Horn Antenna	A.H. Systems	SAS-571	785	2014/1/21	2016/1/31
LN05	LISN	Kyoritsu	KNW-407F	8-1773-2	2014/5/22	2015/5/31
PR12	Pre. Amplifier (1-26G)	Agilent Technologies	8449B	3008A02513	2014/1/21	2015/1/31
PR15	Pre. Amplifier	Anritsu	MH648A	6201156141	2014/6/10	2015/6/30
TR06	Test Receiver (F/W: 3.93 SP2)	Rohde & Schwarz	ESU26	100002	2014/9/5	2015/9/30
TR09	Test Receiver (F/W : 4.43 SP3)	Rohde & Schwarz	ESU8	100386	2014/2/4	2015/2/28

The measuring equipment, which was utilized in performing the tests documented herein, has been calibrated in accordance with the manufacturer's recommendations for utilizing calibration equipment, which is traceable to recognized national standards.

SGS RF Technologies Inc. Page 29 of 29